Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	1	(repairing adj3 group adj2 elements)	US-PGPUB	OR	OFF	2005/10/19 15:41
L3	4	(repairing adj5 elements) and inhibiting	US-PGPUB	OR	OFF	2005/10/19 15:41

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DB = east

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L14	736	(test$3 near5 (memory or element$1 or components or unit$1 or IC$1 or device$1 or circuit$1)) and (detect$4 near5 (error$1 or fault$1 or defect$1)) and (repair$4 or replac45) and inhibit$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:57
L15	488	((test$3 near5 (memory or element$1 or components or unit$1 or IC$1 or device$1 or circuit$1)) same (detect$4 near5 (error$1 or fault$1 or defect$1))) and (repair$4 or replac$5) and inhibit$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:55
L16	364	((test$3 adj4 (memory or memories or element$1 or components or unit$1 or IC$1 or device$1 or circuit$1)) same (detect$5 near5 (error$1 or fault$1 or defect$1))) and (repair$4 or replac$5) and inhibit$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:55
L17	73	((test$3 near5 (memory or element$1 or components or unit$1 or IC$1 or device$1 or circuit$1)) same (detect$4 near5 (error$1 or fault$1 or defect$1)) same (repair$4 or replac$5)) and inhibit$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:55
L18	190	(test$3 adj4 (memory or memories or element$1 or component$1 or unit$1 or IC$1 or device$1 or circuit$1)) and (detect$5 near5 (error$1 or fault$1 or defect$1)) and ((repair$4 or replac$5) same inhibit$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:55
L19	153	(test$3 adj4 (memory or memories or element$1 or component$1 or unit$1 or IC$1 or device$1 or circuit$1)) and (detect$5 adj5 (error$1 or fault$1 or defect$1)) and ((repair$4 or replac$5) same inhibit$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:59
L20	41	(test$3 adj4 (memory or memories or element$1 or component$1 or unit$1 or IC$1 or device$1 or circuit$1)) and (detect$5 adj5 (error$1 or fault$1 or defect$1)) and ((repair$4 or replac$5) near15 inhibit$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:56

L21	33	(test$3 adj4 (memory or memories or element$1 or component$1 or unit$1 or IC$1 or device$1 or circuit$1)) and (detect$5 adj5 (error$1 or fault$1 or defect$1)) and ((repair$4 or replac$5) near10 inhibit$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:56
L22	438	test$3 and (detect$5 adj5 (error$1 or fault$1 or defect$1)) and ((repair$4 or replac$5) near5 (element$1 or component$1)) and inhibit$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 15:01
L23	16	test$3 and (detect$5 adj5 (error$1 or fault$1 or defect$1)) and (((repair$4 or replac$5) near5 (element$1 or component$1)) same inhibit$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 15:01

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